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## ***Postscript***

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This special issue of JSA is published in honor of Professor Keisuke Goto, who has been contributed to the improvement of the traceability of AES, in order to celebrate his retirement from Nagoya Institute of Technology (NIT) in 2006. His ever-lasting efforts and enthusiasms on the development of a noble CMA and its application to the construction of the standard absolute AES spectrum database have made great contributions to the improvement of accuracy of quantification.

When I first met with him and his spectra in ~1994, I was a student and too young to understand excellence behind his data. Recently, I have been involved in research works with him and finding that his machine and data are “art” and he is a “Takumi” (please see *Preface*)

day by day. Now I am really proud of working with him.

He continues to publish absolute spectra at AIST after his retirement from NIT. His enthusiasms and way of thinking always encourage us. He teaches us without saying many things. This is also a Takumi. An apprentice of a Takumi should learn from thinking by oneself what, how and why a Takumi does for his/her art. Don’t you think that this is also important for practical surface analysts?

On behalf of the JSA editorial committee, I would like to say congratulation on his retirement from NIT and his new academic life at AIST, and sincere thanks for his devotion to practical surface analysis, SASJ and JSA.

(T. Nagatomi)

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## ***JSA Journal of Surface Analysis***

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